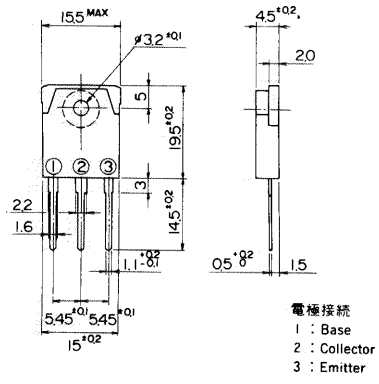
2SC2769

FUJI POWER TRANSISTOR

TRIPLE DIFFUSED PLANER TYPE
HIGH SPEED SWITCHING

■ Outline Drawings

TO-3P



JEDEC	-
EIAJ	SC-65

■ Features

- **High voltage,High speed switching**
- **Low saturation voltage**
- **High reliability**

■ Applications

- **Switching regulators**
- **DC-DC convertor**
- **Solid State Relay**
- **General purpose power amplifiers**

■ Maximum ratings and characteristics

● **Absolute maximum ratings (Tc=25°C unless otherwise specified)**

Item	Symbol	Ratings	Unit
Collector-Base voltage	V_{CBO}	250	V
Collector-Emitter voltage	V_{CEO}	200	V
Collector-Emitter voltage	$V_{CEO(SUS)}$	200	V
Emitter-Base voltage	V_{EBO}	7	V
Collector current	I_C	10	A
Base current	I_B	5	A
Collector power disspation	P_C	100	W
Operating junction temperature	T_j	+150	℃
Storage temperature	T_{stg}	-55 to +150	℃

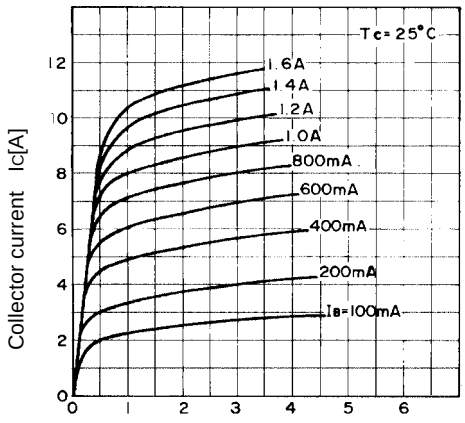
● **Electrical characteristics (T_C =25°C unless otherwise specified)**

Item	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Collector-Base voltage	V_{CBO}	I_{CBO} = 0.1mA	250			V
Collector-Emitter voltage	V_{CEO}	I_{CEO} = 10mA	200			V
Collector-Emitter voltage	$V_{CEO(SUS)}$	I_C = 1A	200	-		V
Emitter-Base voltage	V_{EBO}	I_{EBO} = 0.1mA	7	-		V
Collector-Base leakage current	I_{CBO}	V_{CBO} = 250V		-	0.1	mA
Emitter-Base leakage current	I_{EBO}	V_{EBO} = 7V		-	0.1	mA
D.C. current gain	h_{FE}	I_C = 2A, V_{CE} = 5V	20		60	
Collector-Emitter saturation voltage	$V_{CE(Sat)}$	I_C = 2A, I_B = 0.8A			0.2	V
Base-Emitter saturation voltage	$V_{BE(Sat)}$	I_C = 5A, I_B = 1A			1.1	V
*1	t_{on}	I_C = 6A, I_{B1} = -I_{B2} = 1.2A			0.8	µs
Switching time	t_{stg}	R_L = 10 ohm, Pw = 20µs Duty=<2%			2.0	µs
	t_f				0.5	µs

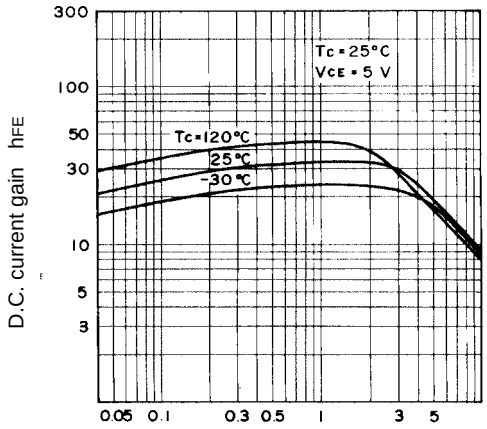
● **Thermal characteristics**

Item	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal resistance	$R_{th(j-c)}$	Junction to case			1.25	°C/W

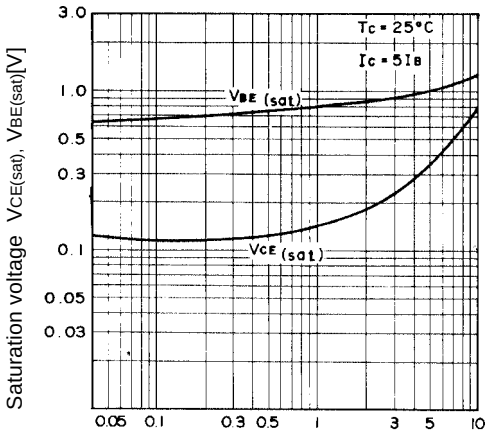
Characteristics



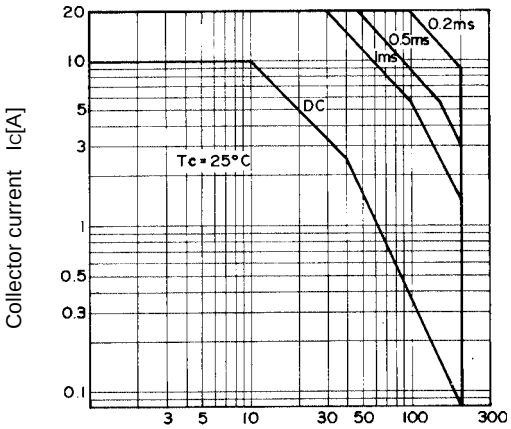
Collector Output Characteristics



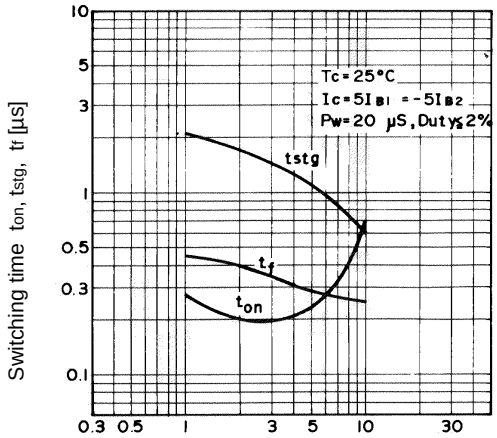
DC Current Gain



Base and Collector Saturation Voltage



Safe Operating Area



Switching Time

***1 Switching Time Test Circuit**